

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Eran Dvir, Eli Haimovich, and Benjamin Shulman  
Assignee: Nova Measuring Instruments, Ltd.  
Title: APPARATUS FOR OPTICAL INSPECTION OF WAFERS DURING  
POLISHING  
Serial No.: 08/497,382 Filed: June 29, 1995  
Batch No.: U26 Date Allowed: November 17, 1997  
Examiner: E. Morgan Group Art Unit: 3203  
Docket No.: M-3417 US

San Jose, California  
February 17, 1998

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Attn: Official Draftsman

COMMISSIONER OF PATENTS AND TRADEMARKS

Washington, D. C. 20231

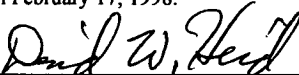
**SUBMISSION OF FORMAL DRAWINGS**

Dear Sir:

Applicants submit seven (7) sheets of formal drawings, consisting of Figures 1, 2, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12, and 13, in the above-named application. If there are any questions regarding these drawings, please call the undersigned at (408) 453-9200.

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner of Patents and Trademarks, Washington, D.C. 20231,

on February 17, 1998.



Attorney for Applicant(s)

12 Feb 98

Date of Signature

Respectfully submitted,



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